## Notic of References Cit d

Application/Control No. 10/629,990	Applicant(s)/Pater Reexamination DEWEY ET AL.	nt Under
Examiner	Art Unit	
Frank S Tsay	3672	Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,878,818 A	03-1999	Hebert et al.	166/382
	В	US-5,443,129 A	08-1995	Bailey et al.	175/45
	С	US-6,003,621 A	12-1999	Murray, James W.	175/79
	D	US-6,354,375 B1	03-2002	Dewey, Charles H.	166/313
	E	US-6,488,095 B2	12-2002	Buytaert, Jean P.	166/382
	F	US-6,499,537 B1	12-2002	Dewey et al.	166/255.1
	G	US-6,648,069 B2	11-2003	Dewey et al.	166/50
	Н	US-			
	-	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	ø					"
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*	* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U			
	V			
	w			
	х			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.